



## N-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DSS}$  60V
- Drain-Source On-Resistance  
 $R_{DS(ON)} 17m\Omega$ , at  $V_{GS} = 10V$ ,  $I_D = 30A$
- Continuous Drain Current at  $T_C = 25^\circ C$   $I_D = 35.1A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

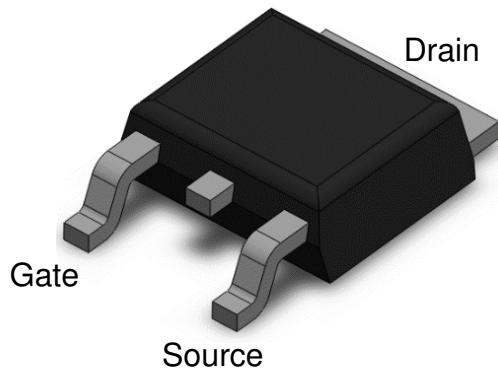
### Description

The CTH3506NS-T52 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application.

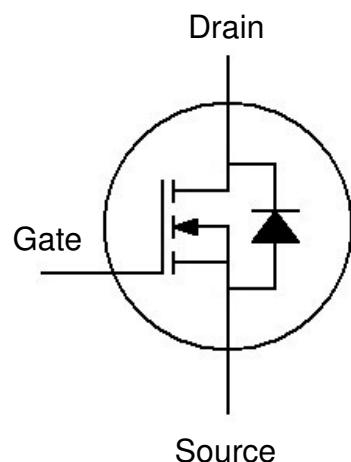
### Applications

- DC/DC Converter
- Power Management
- CCFL inverter

### Package Outline



### Schematic





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### Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Note
V <sub>DS</sub>	Drain-Source Voltage	60	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current @T <sub>c</sub> =25°C	35.1	A	1
I <sub>DM</sub>	Pulsed Drain Current	140	A	1
P <sub>D</sub>	Total Power Dissipation @T <sub>c</sub> =25°C	59.5	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

### Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>θJC</sub>	Thermal Resistance Junction-Case		--	--	2.1	°C /W	1,4



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### Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

#### Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$V_{BDSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$	60	-	-	V	
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS} = 60\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 20\text{V}$ , $V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA	

#### On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 10\text{V}$ , $I_D = 30\text{A}$	-	17	22	$\text{m}\Omega$	3
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$	2.0	-	4.0	V	3

#### Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$C_{iss}$	Input Capacitance	$V_{GS} = 0\text{V}$ , $V_{DS} = 15\text{V}$ $f = 1\text{MHz}$	-	2280	-	pF	
$C_{oss}$	Output Capacitance		-	202	-		
$C_{rss}$	Reverse Transfer Capacitance		-	62	-		

#### Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 30\text{V}$ , $V_{GS} = 10\text{V}$ , $R_G = 3.6\Omega$ , $R_L = 30\Omega$ , $I_D = 1\text{A}$	-	27.7	-	ns	
$T_R$	Rise Time		-	5.1	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	54.2	-		
$T_F$	Fall Time		-	5.5	-		
$Q_G$	Total Gate Charge	$V_{DS} = 48\text{V}$ , $V_{GS} = 4.5\text{V}$ , $I_D = 30\text{A}$	-	10.9	-	nC	
$Q_{GS}$	Gate-Source Charge		-	14.3	-		
$Q_{GD}$	Gate-Drain (Miller) Charge		-	8.3	-		



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### Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 1.0A	-	1.0	1.2	V	1
I <sub>SD</sub>	Body Diode Continuous Current		-	-	1.0	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. The data tested by pulsed , pulse width  $\leq$  300μs , duty cycle  $\leq$  2%
3. Thermal Resistance follow JESD51-3.



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### Typical Characteristic Curves

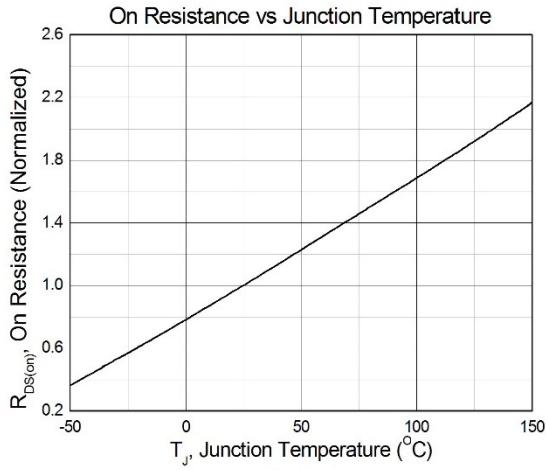


Figure 1

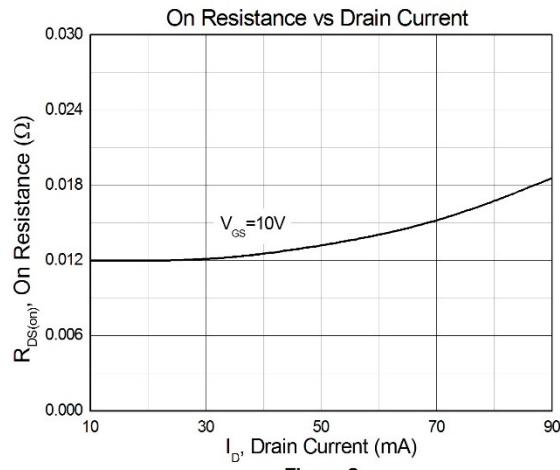


Figure 2

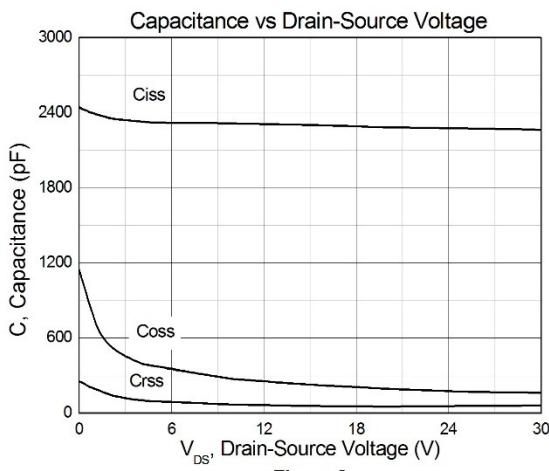


Figure 3

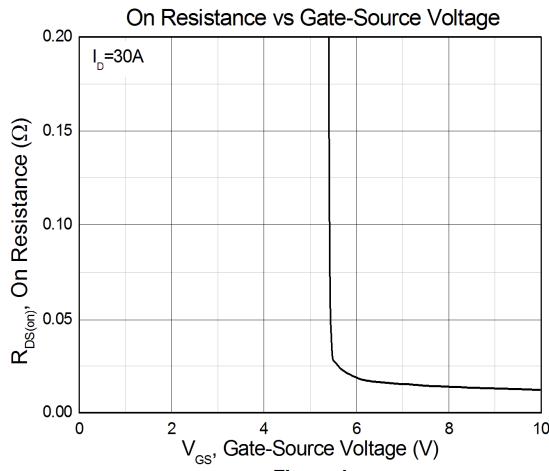


Figure 4

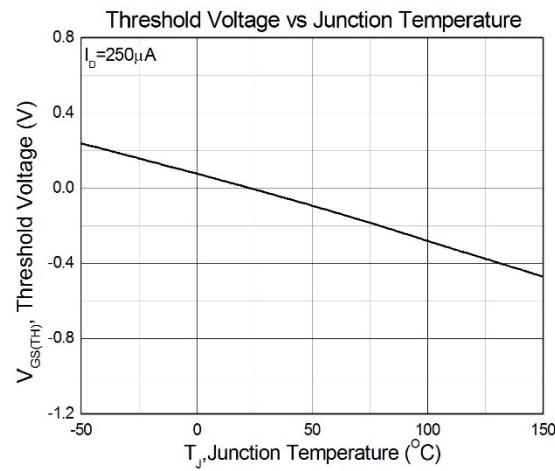
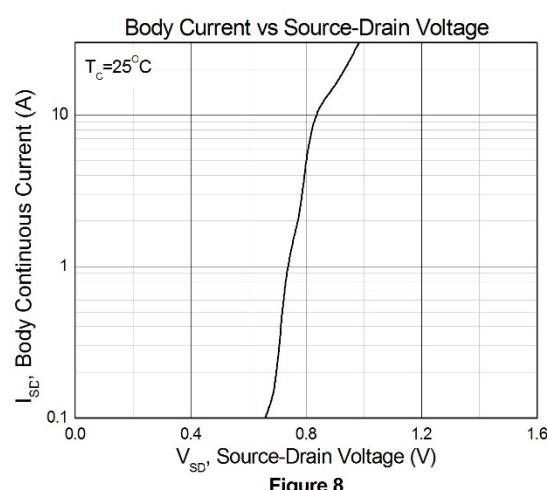
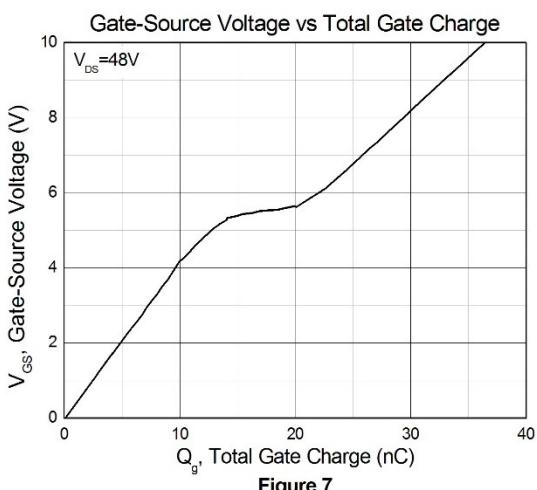
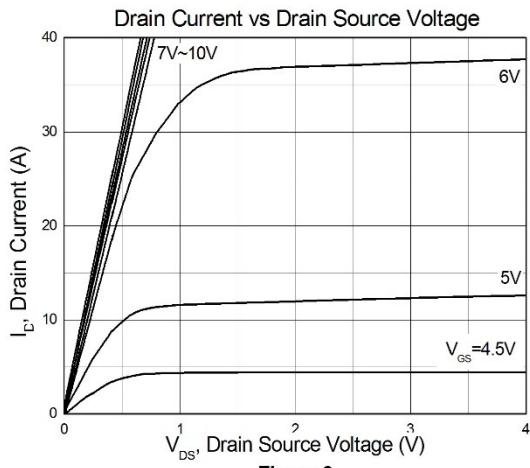


Figure 5



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## Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

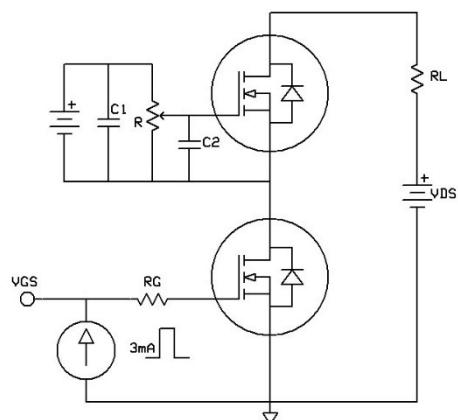


Figure 10: Gate Charge Waveform

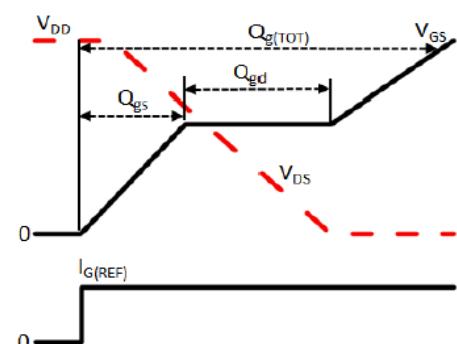


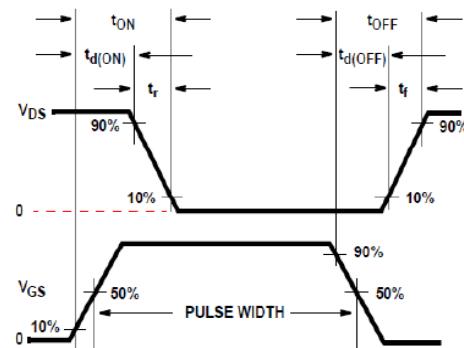
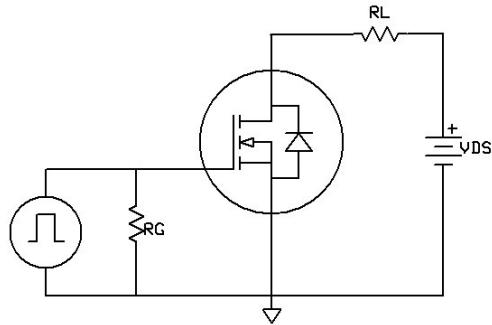
Figure 11: Switching Time Test Circuit

Figure 12: Switching Time Waveform

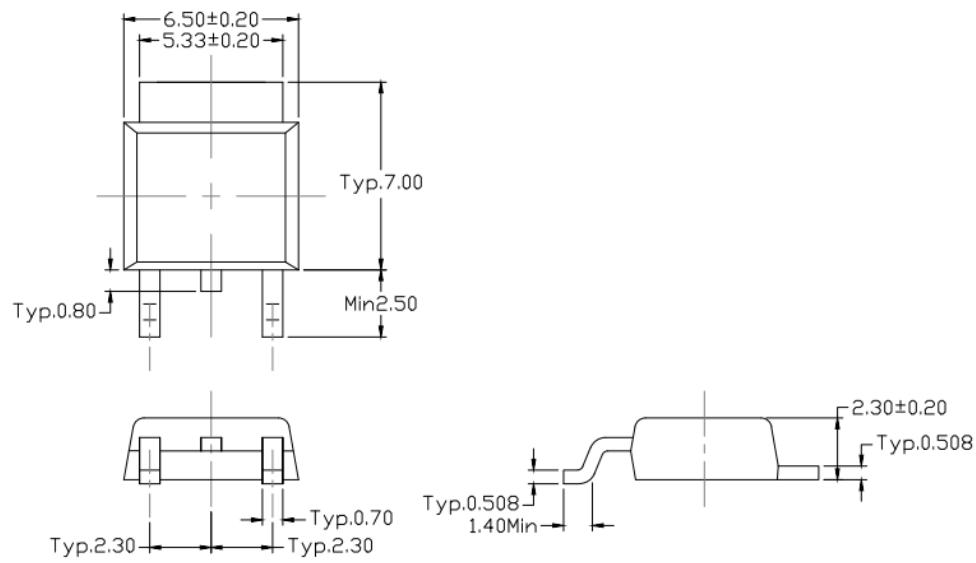


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### Package Dimension (TO-252)



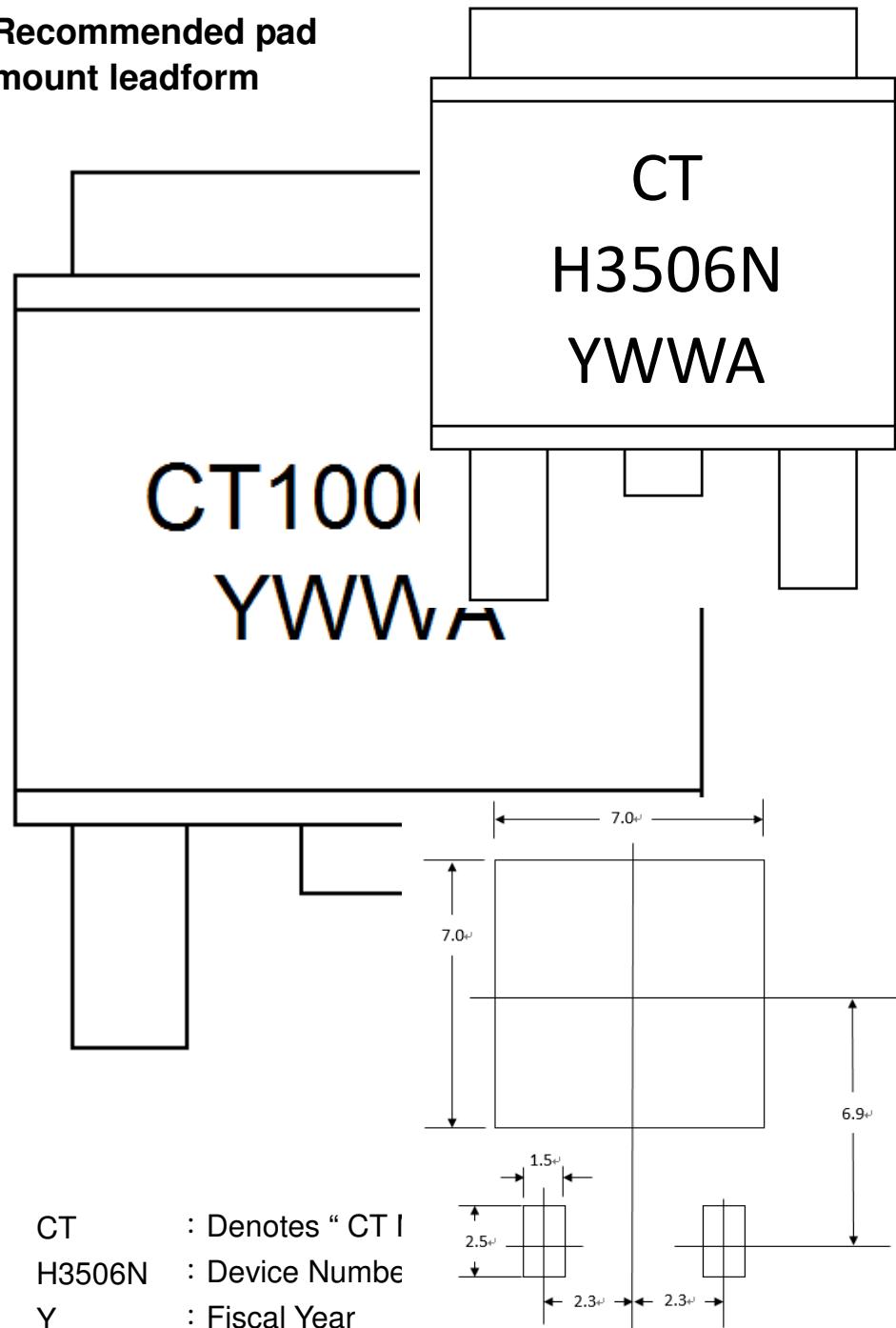


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Dimensions in mm unless otherwise stated

Recommended pad  
mount leadform



layout for surface

CT : Denotes "CT I"  
H3506N : Device Number  
Y : Fiscal Year  
WW : Work Week  
A : Production Code



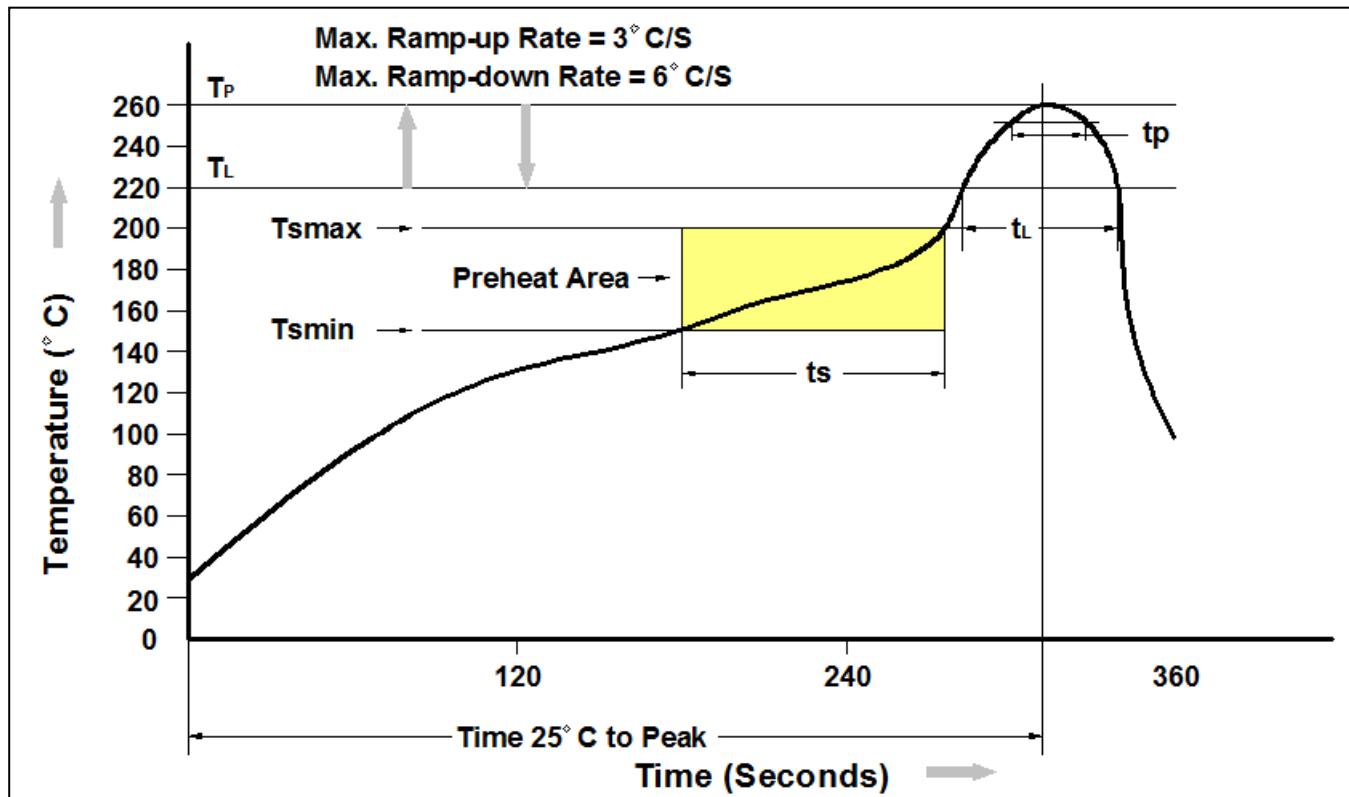
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### Ordering Information

Part Number	Description	Quantity
CTH3506NS-T52	TO-252 Reel	2500 pcs

### Reflow Profile





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Liquidous Temperature ( $T_L$ )	217°C
Time ( $t_L$ ) Maintained Above ( $T_L$ )	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time ( $t_P$ ) within 5°C of 260°C	30 seconds
Ramp-down Rate ( $T_P$ to $T_L$ )	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.

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